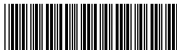


Search Notes**Application/Control No.**

10/672,010

Examiner

ALEX LIEW

**Applicant(s)/Patent under
Reexamination**

SHIBUYA ET AL.

Art Unit

2624

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
382/141-152 limited to text search	2/2/2007	AL
382/181-231 limited to text search	2/21/2007	AL
Consulted with Joseph Mancuso	2/21/2007	AL
Consulted with Samir Ahmed	2/22/2007	AL
382/141-152 limited to text search 382/181-231 limited to text search	5/29/2008	AL